

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/519,006	SPECHT ET AL	
Examiner	Art Unit	
LOIS ZHENG	1793	

	SEAR	CHED	
Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH N (INCLUDING SEAR		<u> </u>
	DATE	EXMR
Inventorship search	9/14/2008	LLZ
UPdated EAST search	9/14/2008	LLZ